

AZtecOne EDS System with X-Max[®] SDD

Adding chemical analysis to your sample investigation

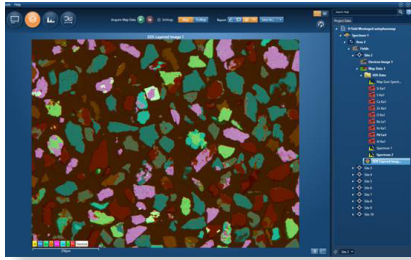


The combination of the simple-to-use yet powerful **AZtecOne** EDS analysis software with the proven stability and accuracy of the **X-Max^N** 20 Silicon Drift Detector, adds a materials characterisation capability to your Scanning Electron Microscopy.

System summary

- The ideal solution for carrying out a complex task like EDS as quickly and as easily as possible.
- No need for advanced knowledge of the EDS technique
 - Oxford Instruments' technology ensures that you can depend on the elements being automatically detected and the correct results being reported
- Streamlined interface to minimise the number of steps to achieve the right results
 - Users can be trained in a matter of minutes
 - No need for the infrequent user to be retrained every time they need to perform an analysis
 - From image to report in seconds





X-Ray Mapping

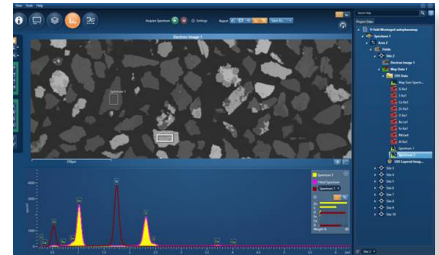
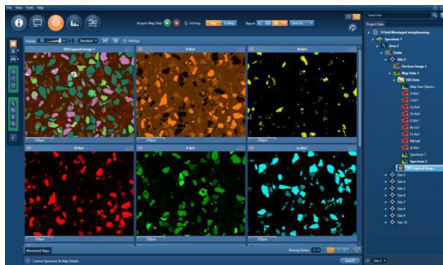
Quickly see what the chemistry of your sample is and where it is distributed

- Layered Image with colour key, helping to visualise both phase and element distribution in a single image
- TruMap - advanced functionality eliminates common artefacts and ensures that users have confidence that they see the true element distribution (Option with AZtecOne only)

Spectrum Acquisition

For when a more detailed analysis is required

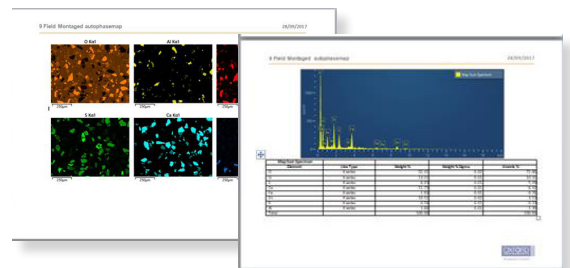
- Elements automatically detected and identified using advanced Tru-Q® technology
- Composition is displayed instantly in the MiniQuant viewer
- Acquire from point, rectangular, elliptical and freehand regions



X-Ray Linescanning

Visualise compositional variation along a line

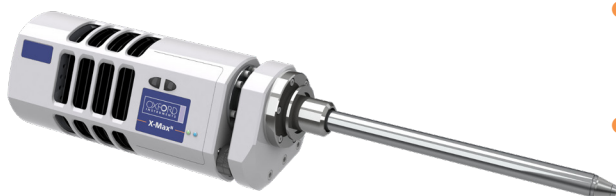
- Normalise display to compare major and trace element variations easily
- Queue up multiple linescans for unattended analysis



Reporting

Quick and easy

- Intuitive content selection allowing report generation in seconds
- Choose to Print, Save or Email
- Personalise reports by adding a company logo



Hardware

- Proven technology and reliability of the X-Max silicon drift detector and electronics deliver accurate quantitative results at all count rates
- Detector chip size options:
 - Standard 20mm² <127eV at MnKα - Guaranteed at 50Kcps
- Peak position is guaranteed to change by no more than 1 eV between 1,000 cps and 100,000 cps

Visit nano.oxinst.com/AZtecOne

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